

MICRO-435

Quantum and Nanocomputing

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Mariagrazia Graziano

CIRCUITS BASED ON MT

CIRCUITS BASED ON NT

OBJECTIVES

a)



- SIMPLE CASES

b)



- ARRAY BASED LOGIC CIRCUITS

- OTHER ELEMENTS

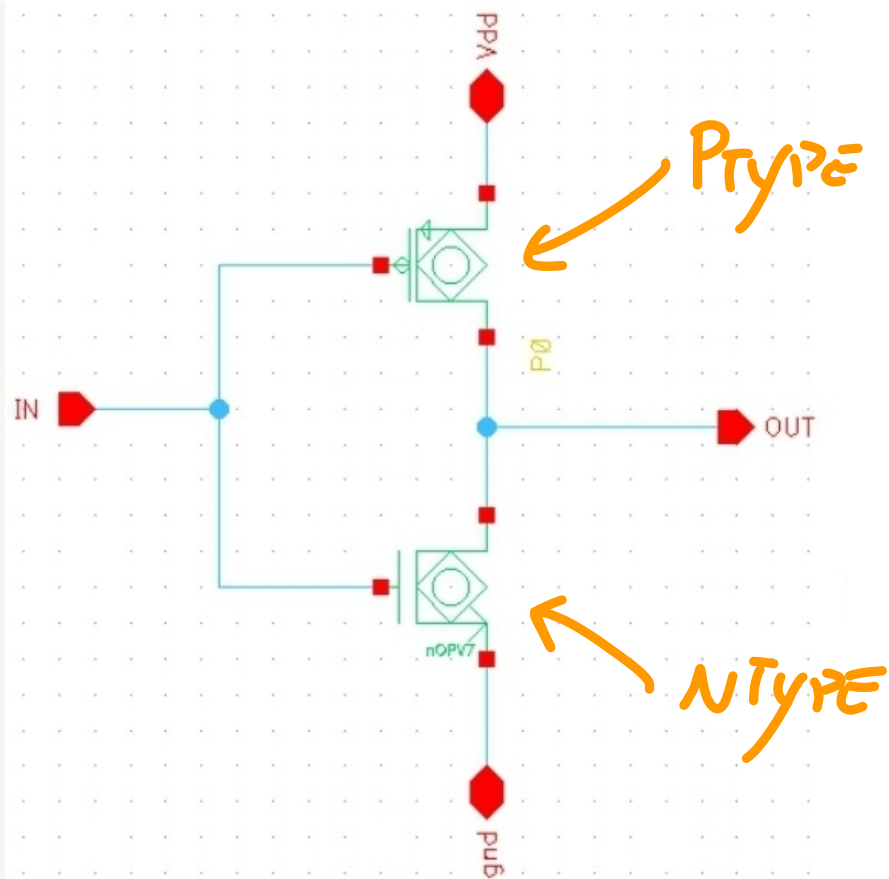
MEMORY ELEMENTS

NEURONS

SENSORS

} OPTIONAL

USE OF η T FOR LOGIC COMPUTATION

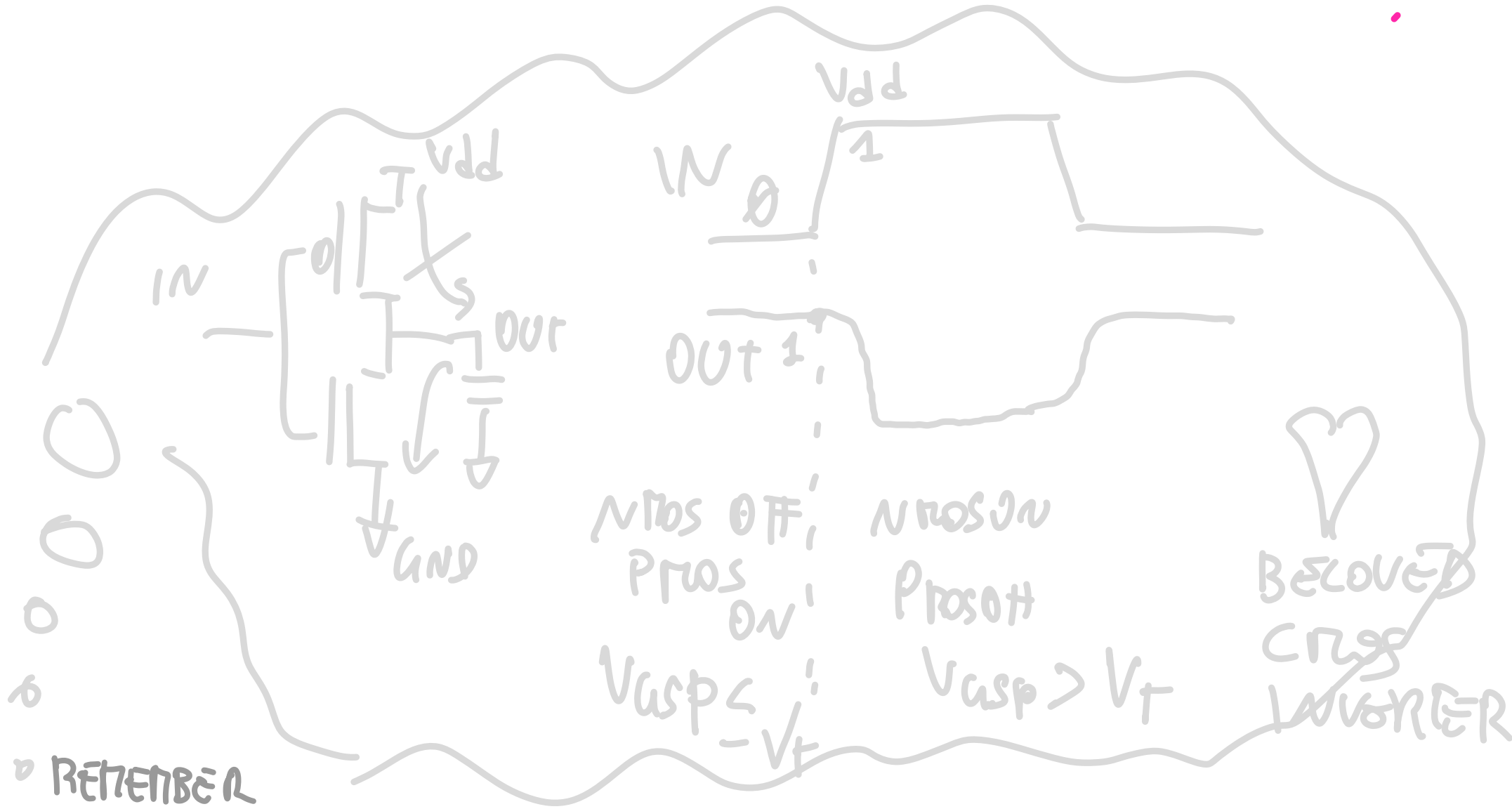


INVERTER

EVEN IF A η .T. WORKS CORRECTLY AND ASSURES GOOD CURRENT AND I_{on}/I_{off} ALONE

NOT NECESSARILY IT WORKS WELL IF CONNECTED TO OTHER η .T. IN A LOGIC GATE

AN OLD GOOD FRIEND ... REMEMBER

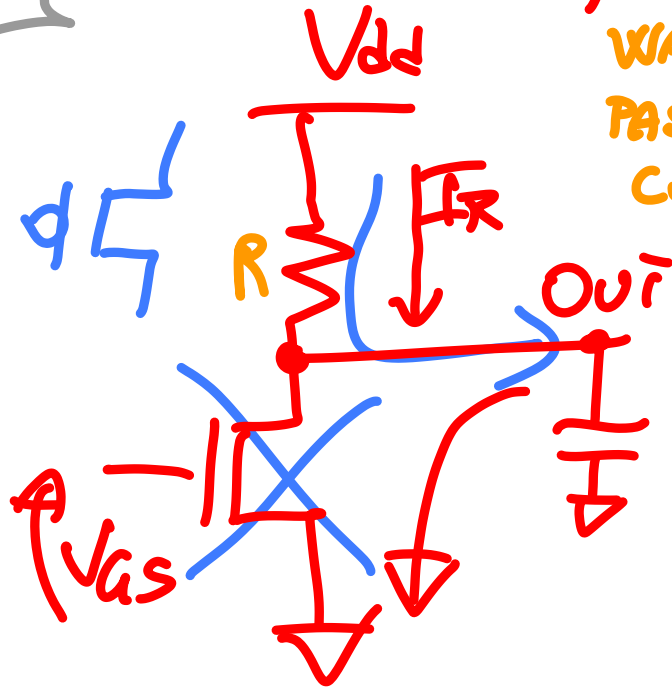


REMEMBER

... AND ALSO REMEMBER THAT ONCE UPON A TIME...
NMOS LOGIC ONLY COULD WORK - NO PMOS!

NMOS LOGIC

WAS COMMON IN THE
PAST WHEN PMOS STILL
COULD NOT BE FABRICATED



if $V_{gs} > 0$
T. ON
Out \rightarrow OFF

if $V_{gs} = 0$
T. OFF

POWER CONSUMPTION BECAUSE THE R IS ALWAYS
"IN CONDUCTION"

COMPLEMENTARY BEHAVIOR WORKS WELL, LET'S KEEP IT!

HOW TO DESIGN & SIMULATE A HT. LOGIC GATE?

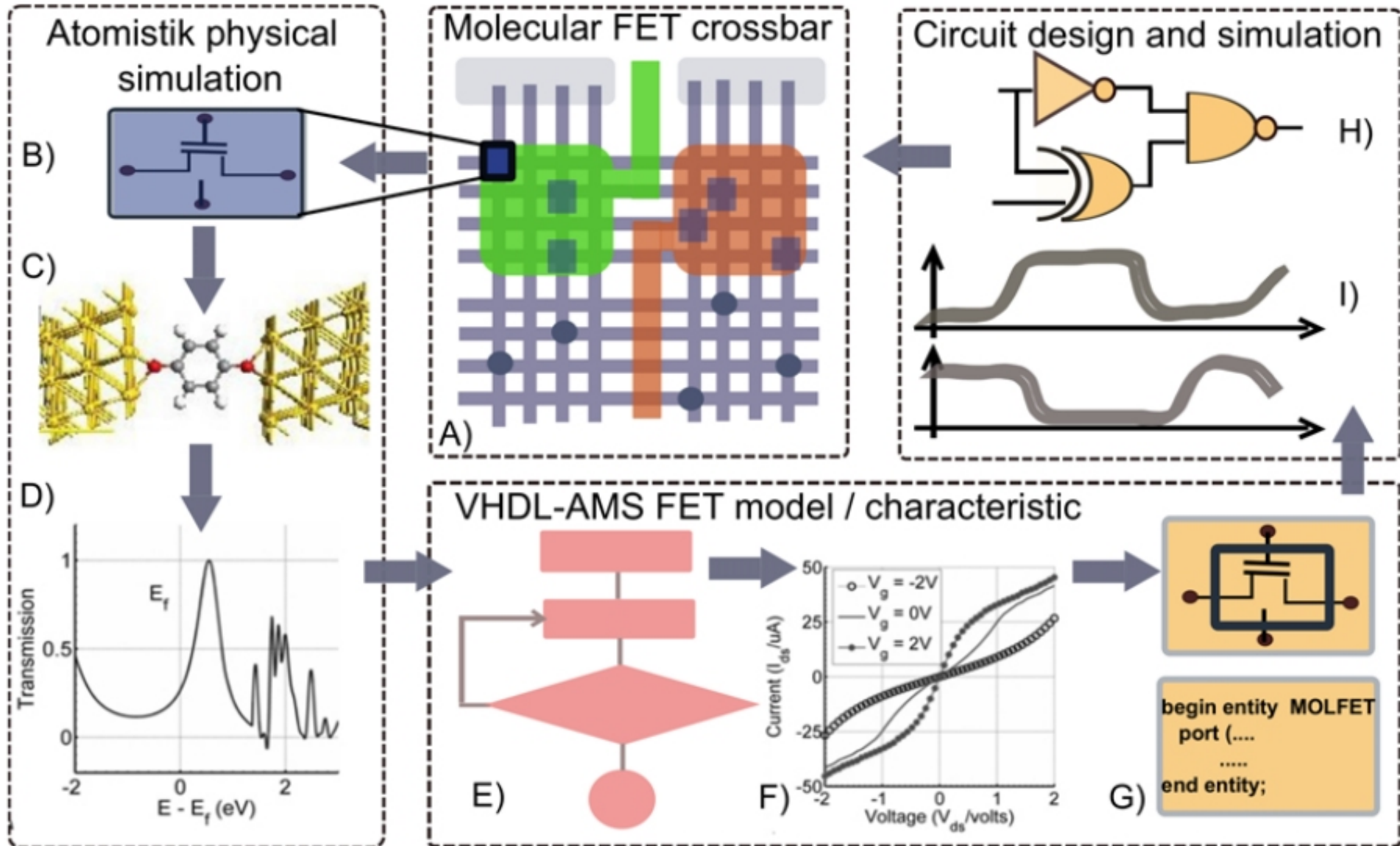
→ QUANTUM ATK AND EEBESD
ARE NOT SUITABLE

→ IN STANDARD TECH

→ SCHEMATIC ENTRY

→ EACH TR. HAS A SYMBOL
AND A TECH MODEL

A METHOD FROM DEVICE PHYSICAL SIMULATION TO CIRCUIT DESIGN AND FUNCTIONAL VERIFICATION



```

ENTITY MOLFET IS
Generic (----);
Port(-----);
End Entity MOLFET;
ARCHITECTURE behav OF MOLFET IS
--Declaration of Quantities
begin
-- DL_SCF (discrete molecular level- self consistent
field) function call.
I -- DL_SCF(EF,E0,U0,G1,G2,A,V,VG1,VG1_back);
END ARCHITECTURE behav;

---- Function DL_SCF is defined in a package
FUNCTION DL_SCF (EF,E0,U0,G1,G2,A,Vds,Vg,Vg_back:REAL)
RETURN REAL IS VARIABLE Ids:REAL;
-----Variable Declarations-----
----- Here all the variables used in the code are
declared
BEGIN
-- self consistent calculations--
G := G1+G2; UL1 := -A*Vg; UL2 := -A*Vg_back; UL :=
UL1+UL2;
E1 := E0+UL; F0 := 1.0/( 1.0 + exp((E0-EF)/KT));
N0 := 2.0 * F0; -- number of electrons
U1 := EF - ((1.0 - VDF)*Vds); U2 := EF + VDF*Vds;
while dU > 1.0e-6 loop
E1 := E0+Uscf+UL; --- New molecular energy levels
F1 := 1.0/( 1.0 + exp((E1-U1)/KT));
F2:= 1.0/( 1.0 + exp((E1-U2)/KT));
N := 2.0*((G1*F1)+(G2*F2))/G; -- Electron population
Uc := U0*(N-N0); -- SCF energy
dU := ABS(Uscf - Uc);
Uscf := Uscf + 0.1*(Uc-Uscf);
end loop;
-- shifting of transmission function--
TQ_SHIFT = shift(TQ,N_SHIFT) -- function for
calculating the shift in transmission function
-- calculating current--
for i in 0 to 100 loop
F11(i):= 1.0/(1.0+exp((E(i)-U1)/KT));
F22(i):= 1.0/(1.0+exp((E(i)-U2)/KT));
FT(i) := F22(i)-F11(i);
SUM1:= SUM1+ (TQ_SHIFT(i)*FT(i)); SUM := dE*SUM1;
Ids := (2.0*Q*Q/H) *SUM;
end loop;
-----
RETURN Ids;
END FUNCTION DL_SCF;

```

VHDL-AMS INCLUDES
THE SCF LOOP

EEBESD METHOD

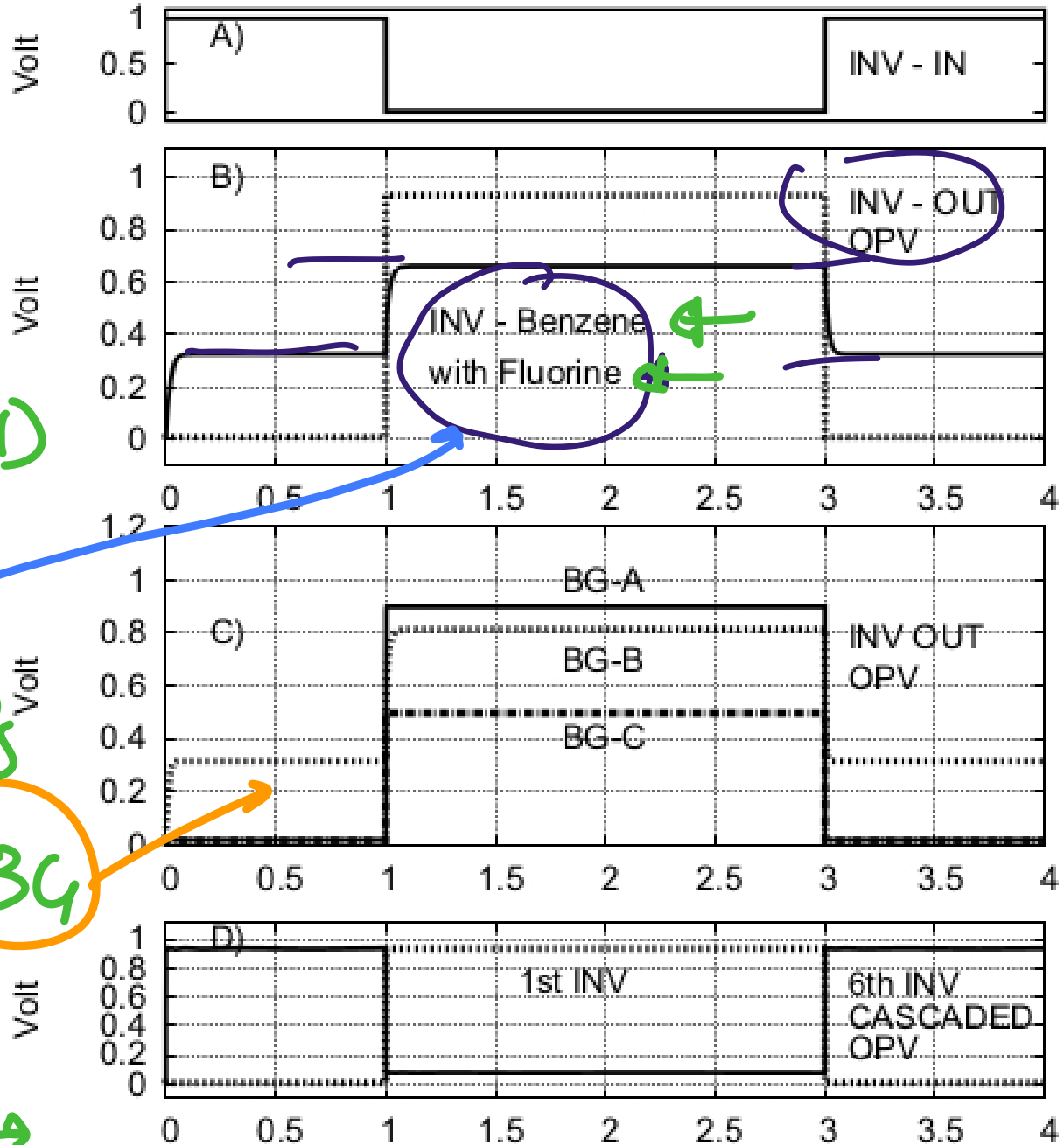
THE LANGUAGE IS
USED TO DESCRIBE THE
CIRCUIT AND AT EACH
STEP, AND FOR EACH
TRANSISTOR THE MODEL
IS CALLED, THE SCF
LOOP IS SOLVED FOR
EACH CONDITION

VHDL-AMS
SIMULATION OF
GATES BASED
ON BENZENE AND

DIFFERENT

ANCORING GROUPS
AND DIFFERENT V_{BG}

6 CASCADED
INV



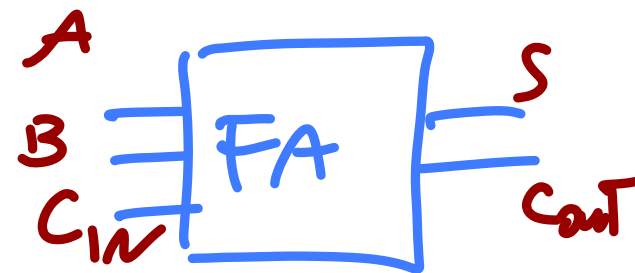
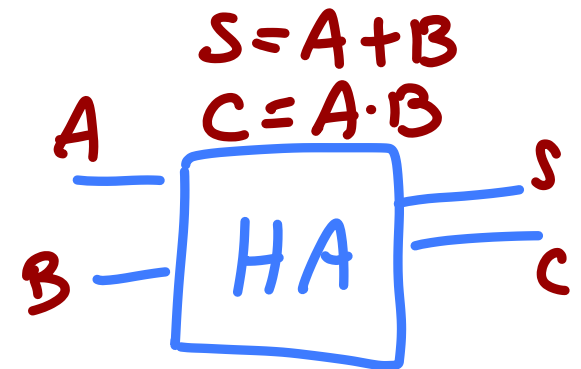
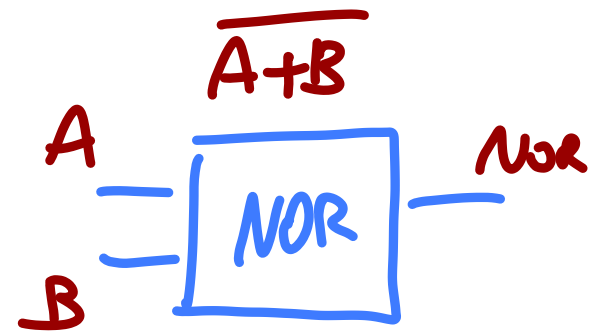
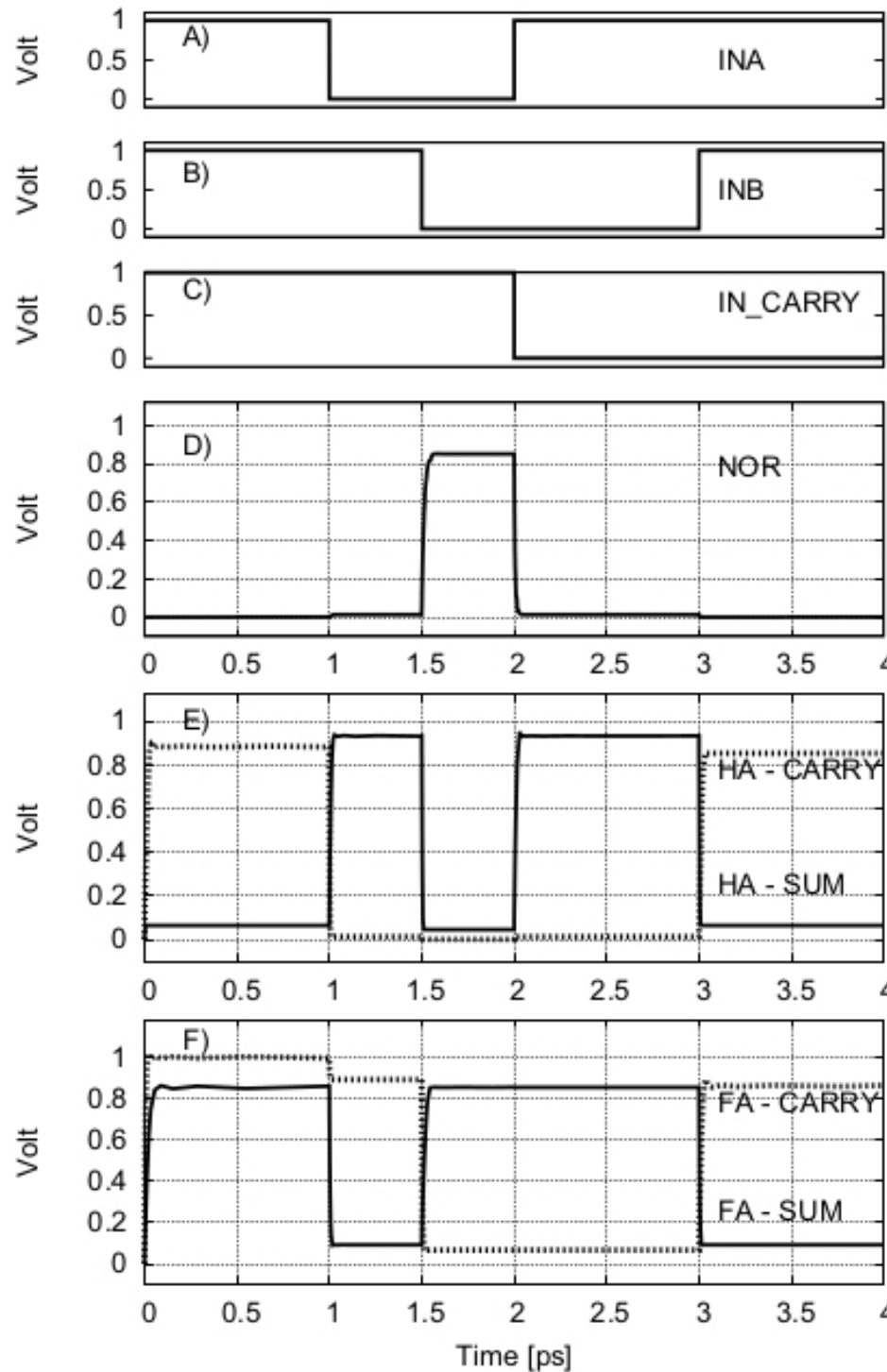
INV

INV

INV

Credits : Ali Zohir

SAME
METHOD
ADOPTED
FOR
OTHER
GATES

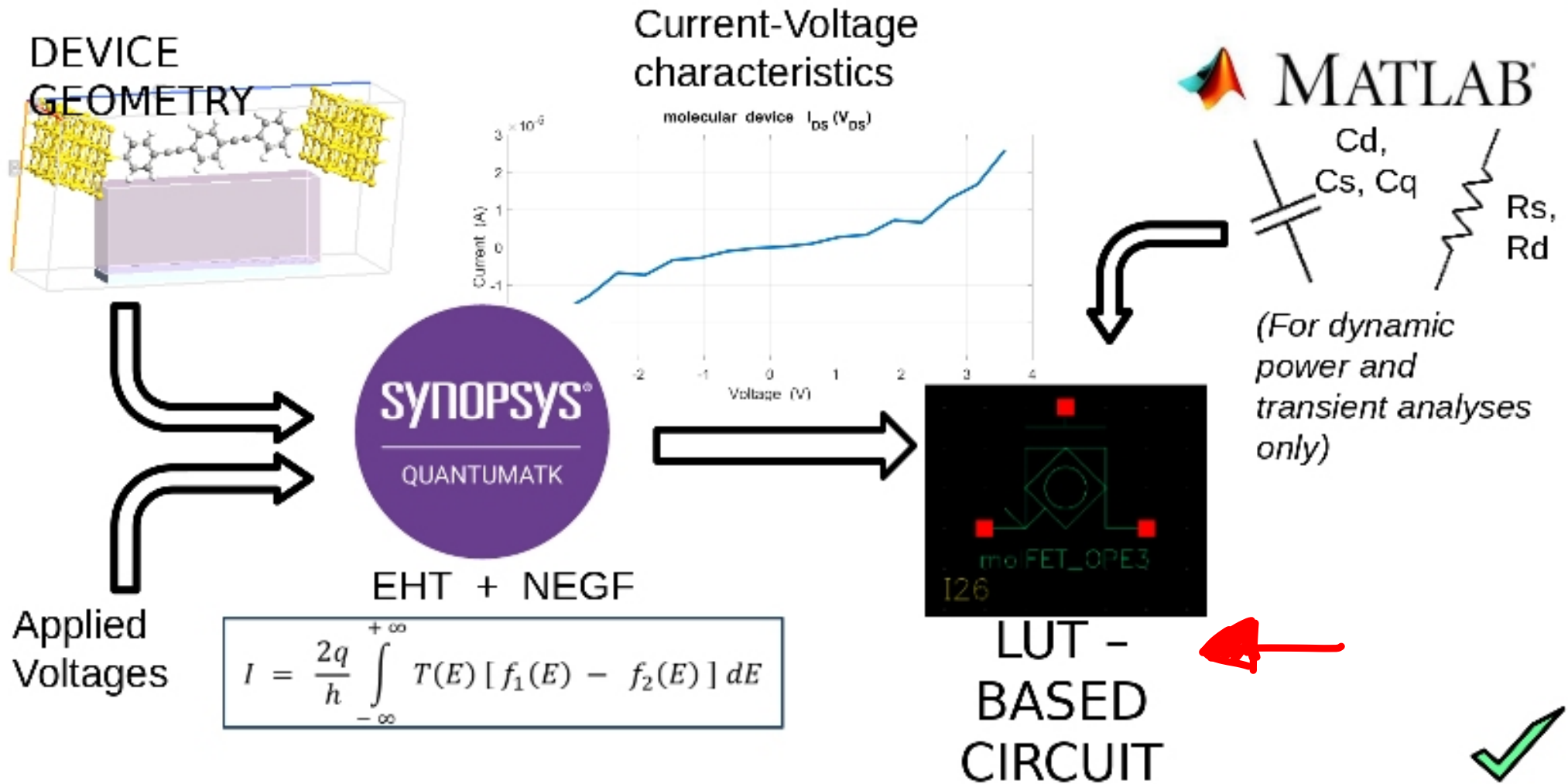


See in a next
slide the T. Table

FROM PHD THESIS
ALI ZAHIR.
IEEE NANARCH.

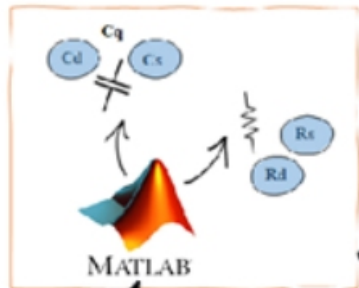
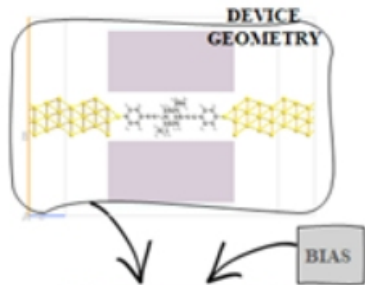
AN EVOLVED RECENT METHOD NOT BASED ON VHDL-ADS

DESIGN & METHODS



DEVICE MODEL

DEVICE PHYSICS



```

veriloga
include "constants.vms"
include "disciplines.vms"

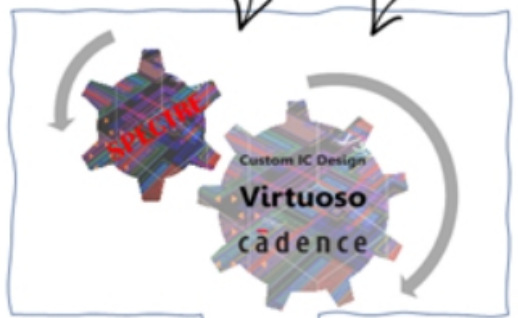
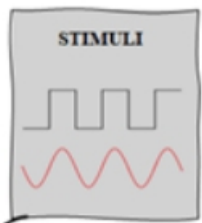
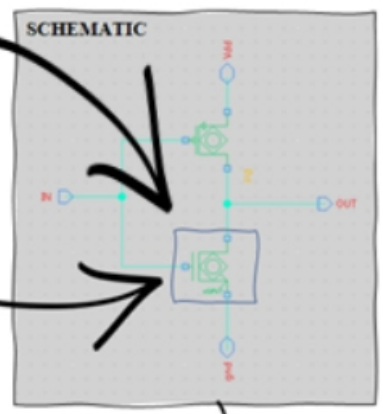
module sSPD(V0,S,I);
  input S;
  electrical I;
  output S;
  electrical I;
  output S;
  electrical I;
endmodule

analog
begin
  I(S) == Disciplines.SP(V0,S, I(S));
end
endmodule
    
```

TABLE CALL

IV.log

-2.000000	0.000000	0.000000e+00
-2.000000	0.200000	3.479012e-12
-2.000000	0.400000	1.393413e-11
-2.000000	0.600000	4.913943e-11
-2.000000	0.800000	2.220101e-10
-2.000000	1.000000	4.768248e-10
-1.500000	0.500000	0.000000e+00
-1.500000	0.200000	9.387324e-13
-1.500000	0.400000	4.717225e-12
-1.500000	0.600000	2.148934e-11
-1.500000	0.800000	4.211493e-11
-1.500000	1.000000	1.396493e-10
-1.000000	0.500000	0.000000e+00
-1.000000	0.200000	9.351393e-12
-1.000000	0.400000	1.428775e-11
-1.000000	0.600000	2.403046e-11
...



DEVICE MODEL

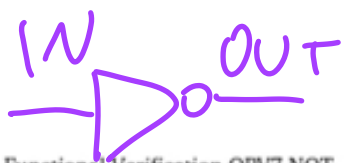
- Functional Analysis
- Static Power Analysis

- Transient Analysis
- Dynamic Power Analysis

Grech's Chiow Spaw
Fabrizio No

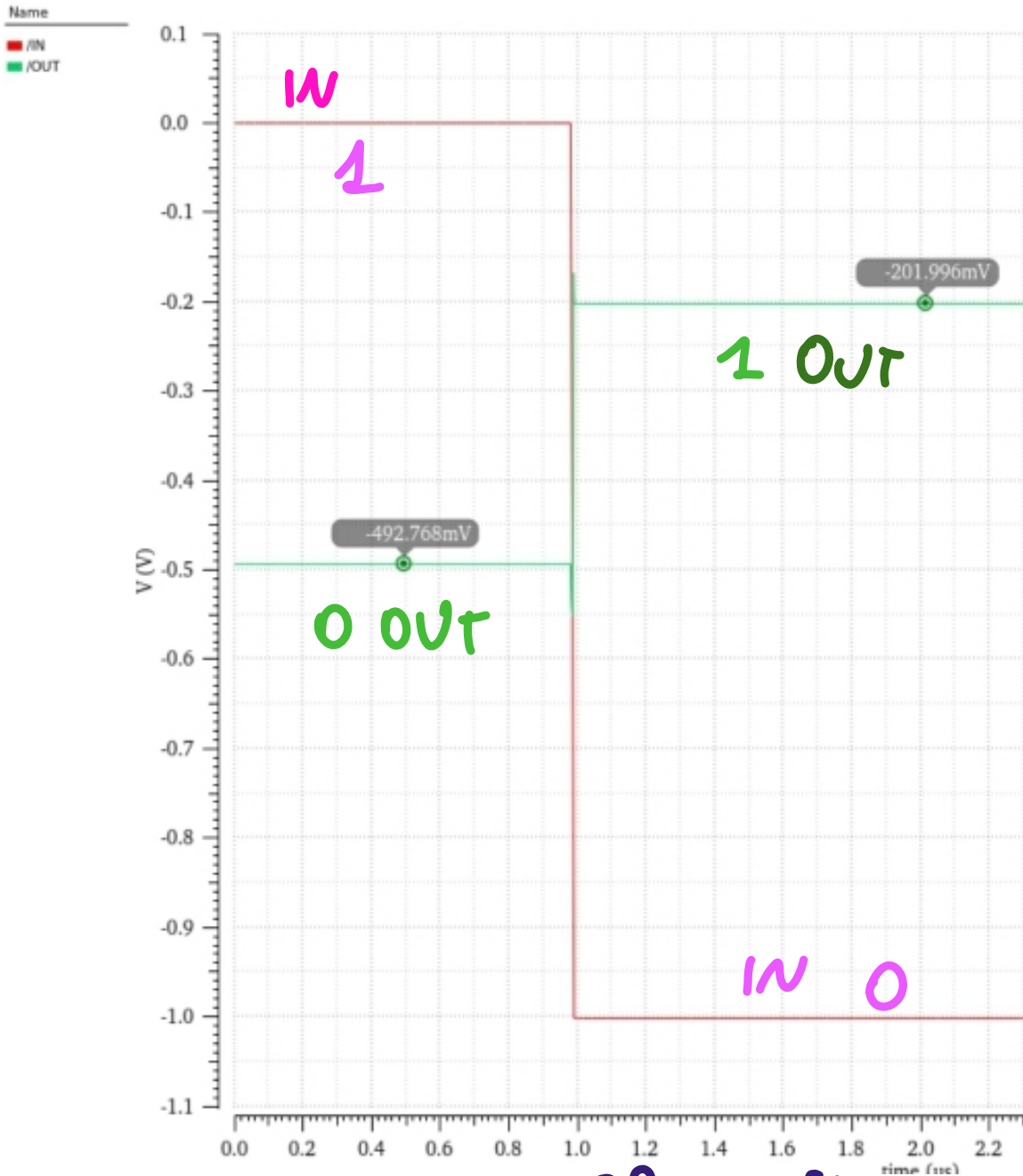
Paper accepted under conditions

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OPV7 INVERTER SIMULATION

Functional Verification OPV7 NOT



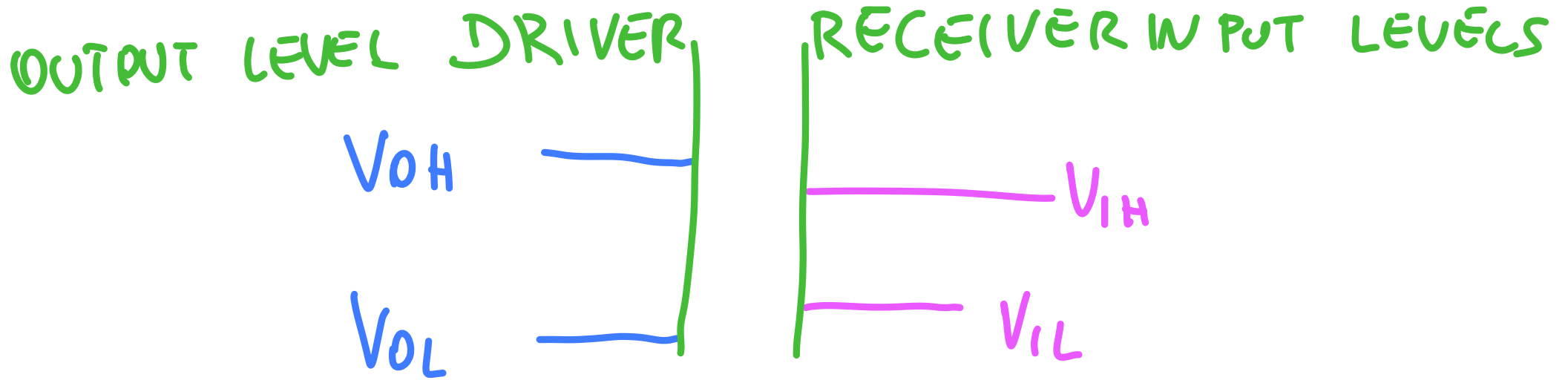
Credits : Chirac Spanso

- BASED ON
CADENCE VIRTUOSO
- VERILOG-A
MODEL OF THE
M.T.

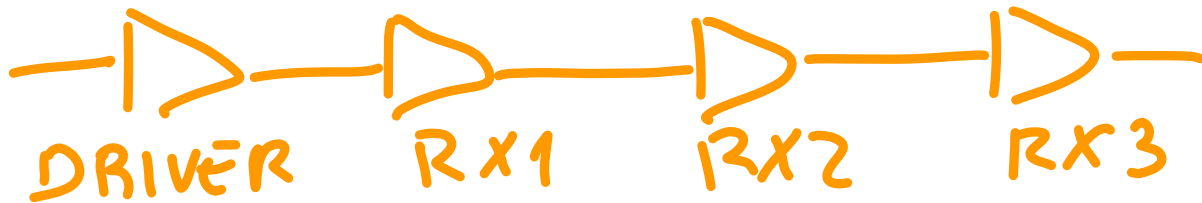
- LOGICALLY IT
WORKS
CORRECTLY
(INVERSION IS OK)

- FUNCTIONALLY
IT DOES NOT
VERY WELL....
WHY?

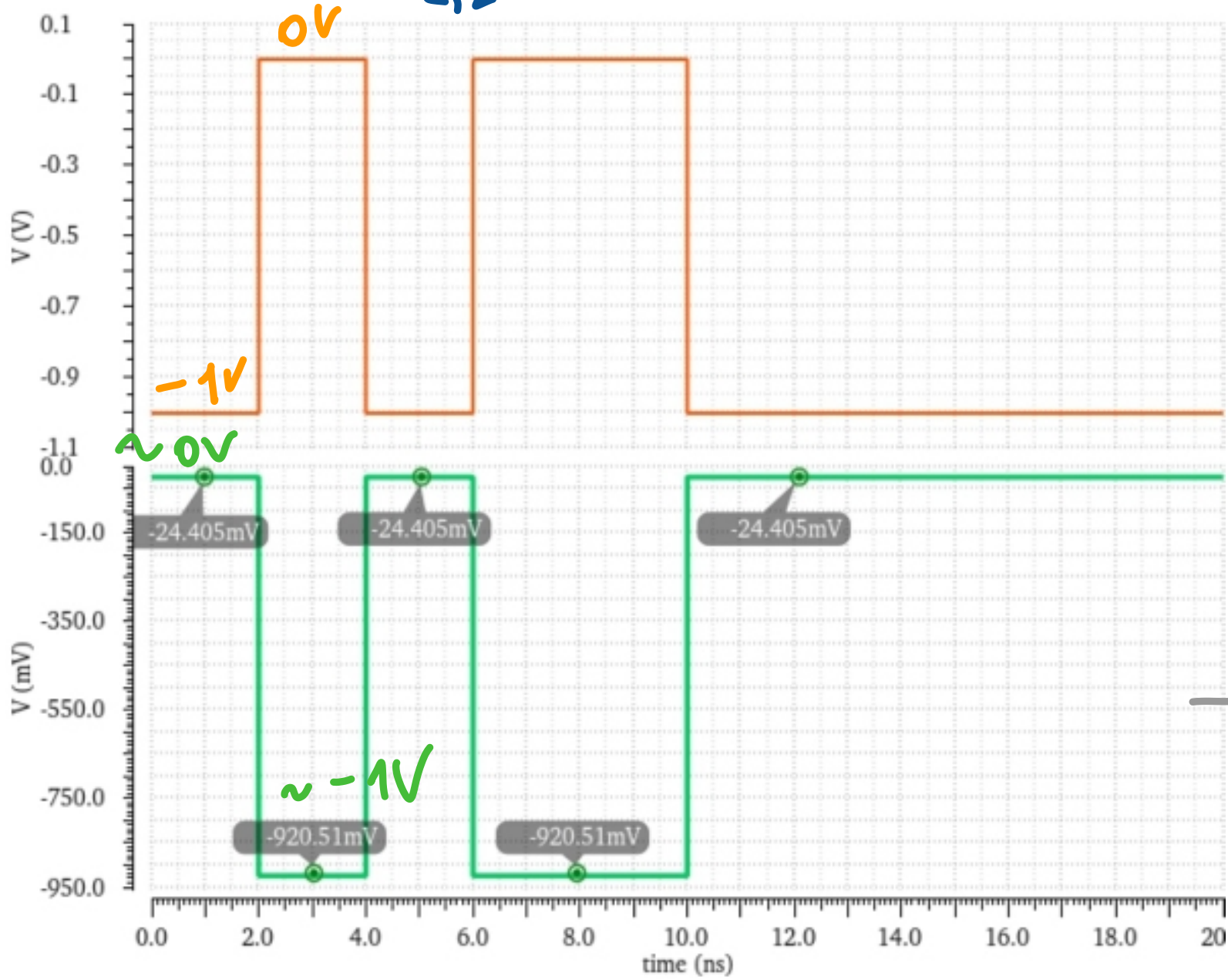
LOGIC INTERFACE



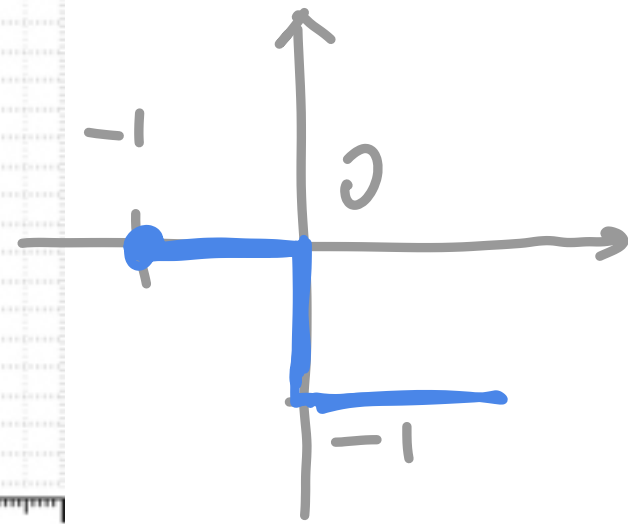
if the output levels reduce at each stage of receivers the logic values might not be recognized and only short chains work



2,2PCP INVERTER



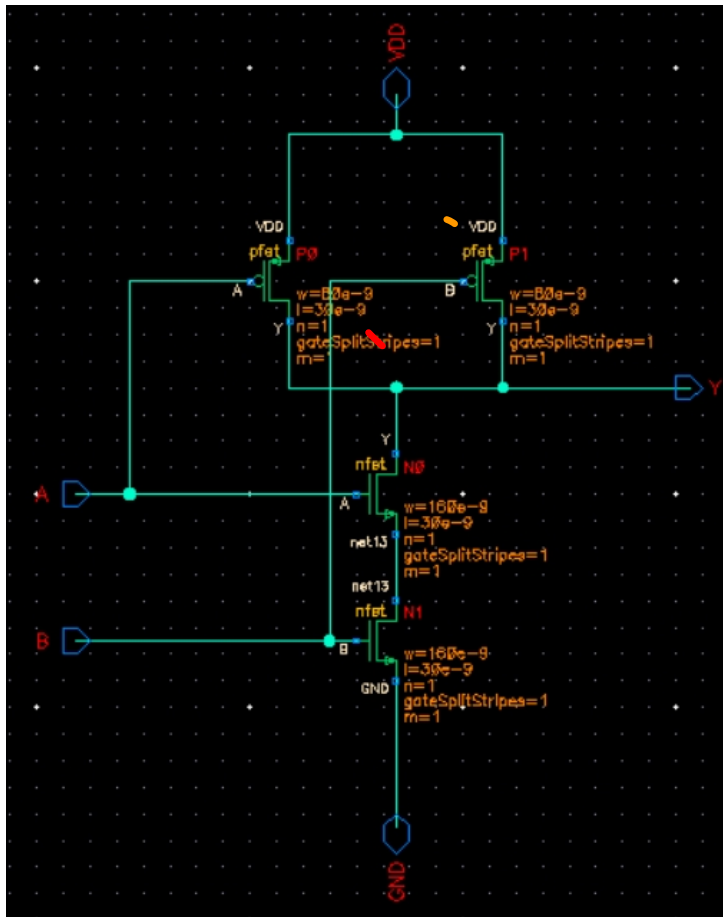
MUCH BETTER CHARACTERISTIC



WE EXPECT THAT SEVERAL STAGES CAN BE CASCADED

OPV7 & PCP COMPARISON

NAND $\overline{A \cdot B}$

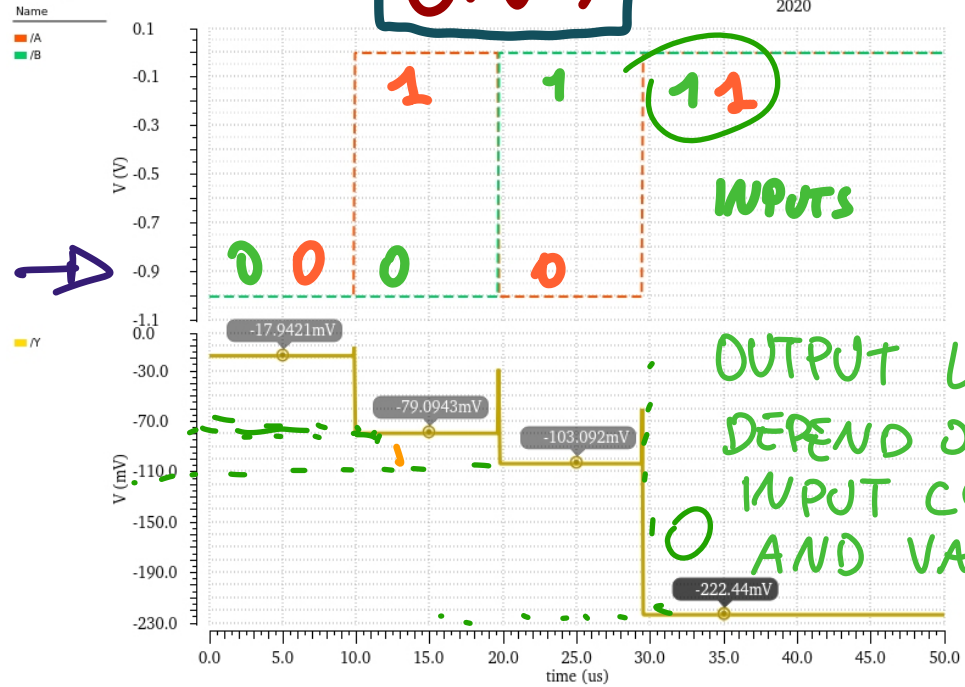


OPV7_NAND Functional Verification

OPV7

Sun Sep 27 20:11:09 2020

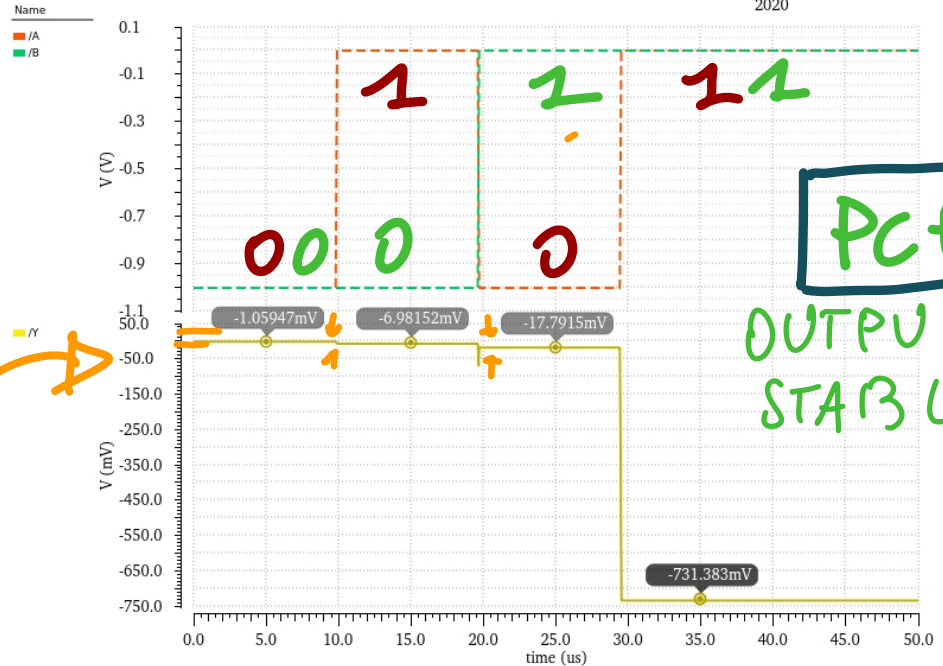
1



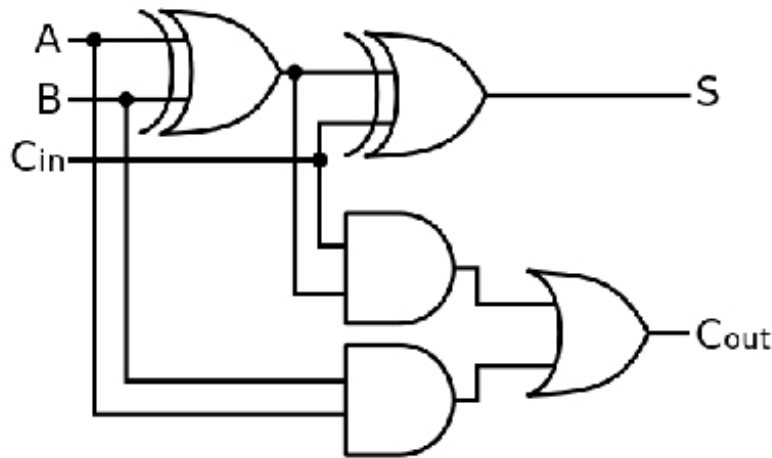
PCP_NAND Functional Verification

Sun Sep 27 20:22:44 2020

1



FULL-ADDER



Full Adder				
A	B	Cin	S	Cout
0	0	0	0	0
0	0	1	1	0
0	1	0	1	0
0	1	1	0	1
1	0	0	1	0
1	0	1	0	1
1	1	0	0	1
1	1	1	1	1

Very often it is considered a proof of promising behavior @ NANOCOMPUTING SCIENTIFIC COMMUNITY

FULL ADDER

OPV7

OPV7_FA Functional Verification

Mon Sep 28 16:03:41 2020 1

Name

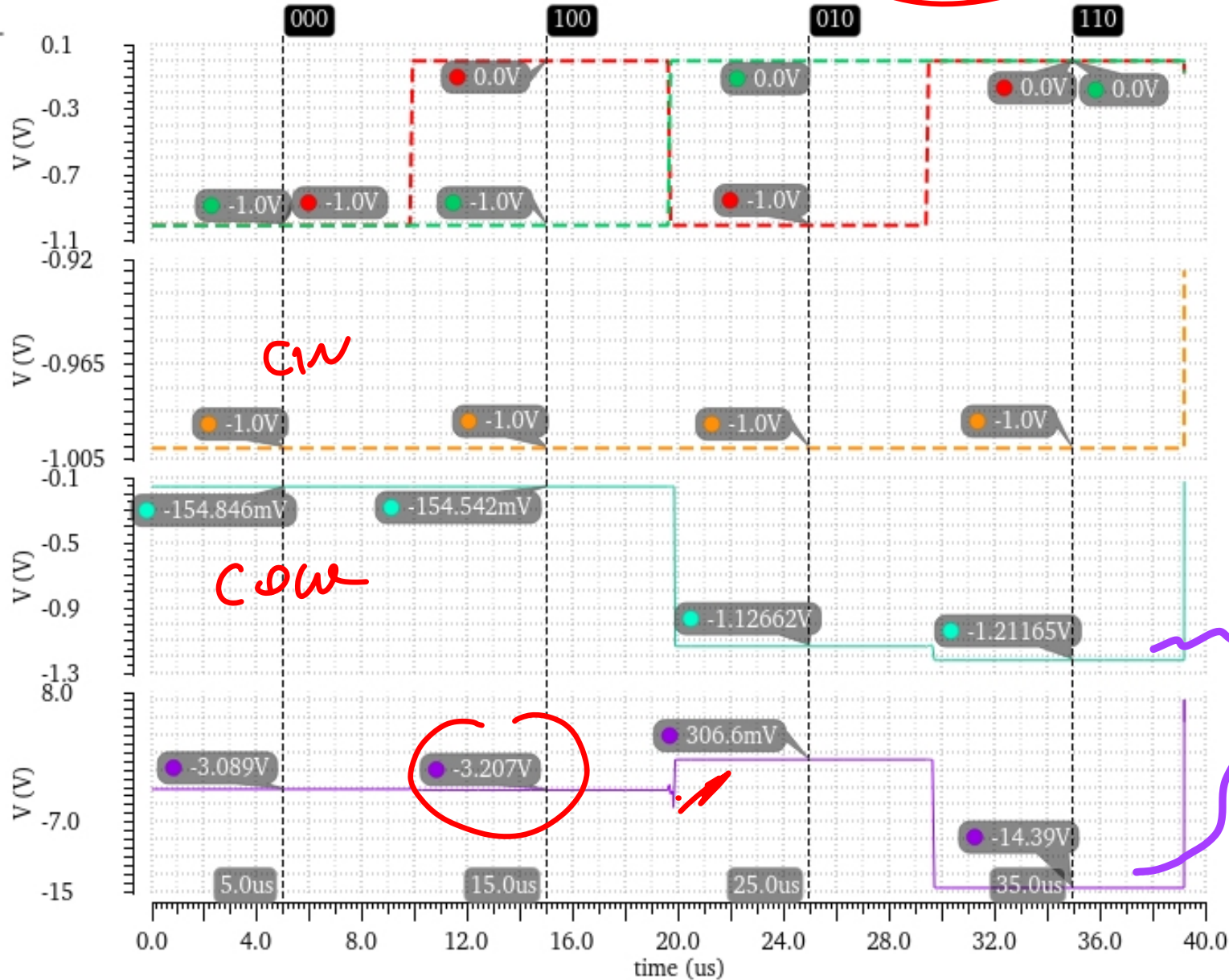
/A

/B

/Cin

/Cout

/S



A13

C1N

C0W

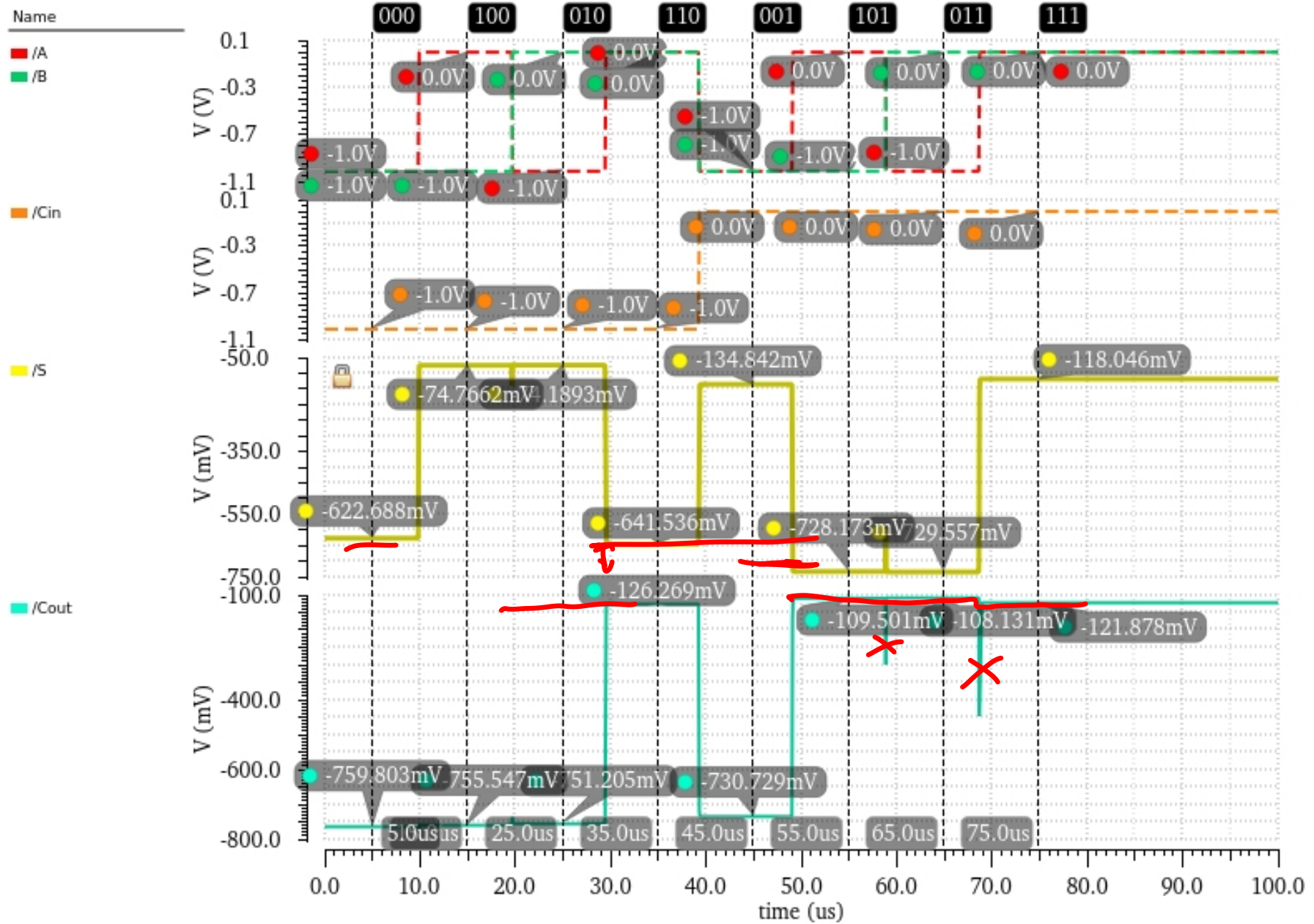
SUH

levels are unstable

PCP FULLADDER

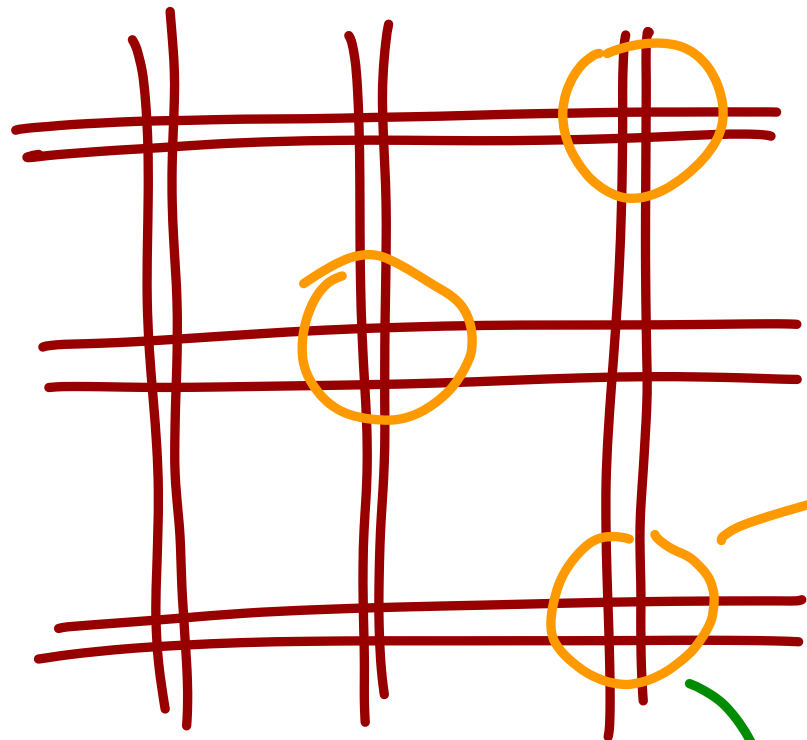
PCP_FA Functional Verification

Mon Sep 28 15:42:31 2020 1



HOW CAN THE N.T. BE ORGANIZED?

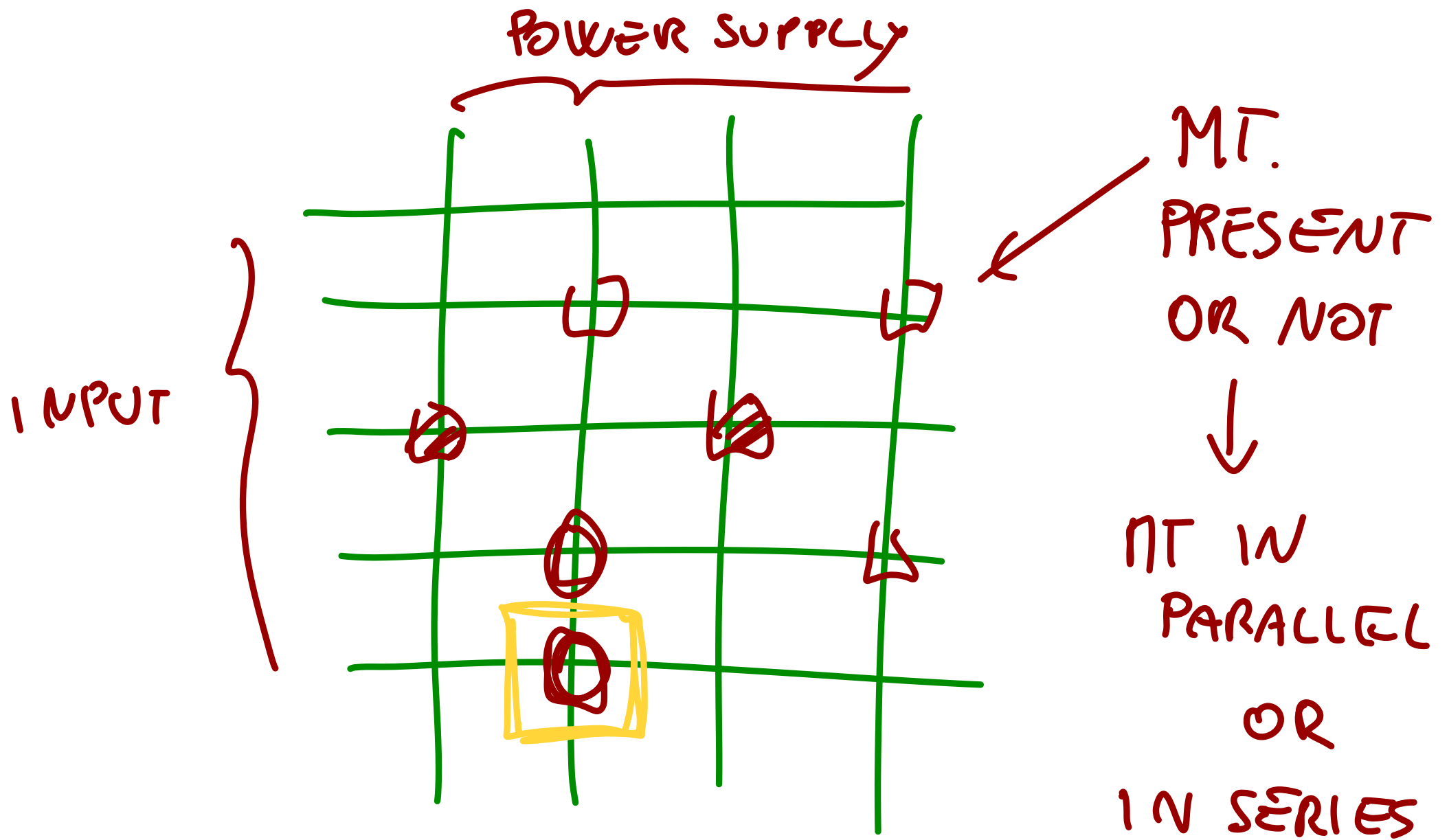
FOR ALL N.T. DEVICES



VERY REGULAR
ARRAY - MATRIX

AT. INTERSECTION
POINTS — DQAPS
AR FABRICATED

TR. CREATED
SELECTIVELY



INPUT

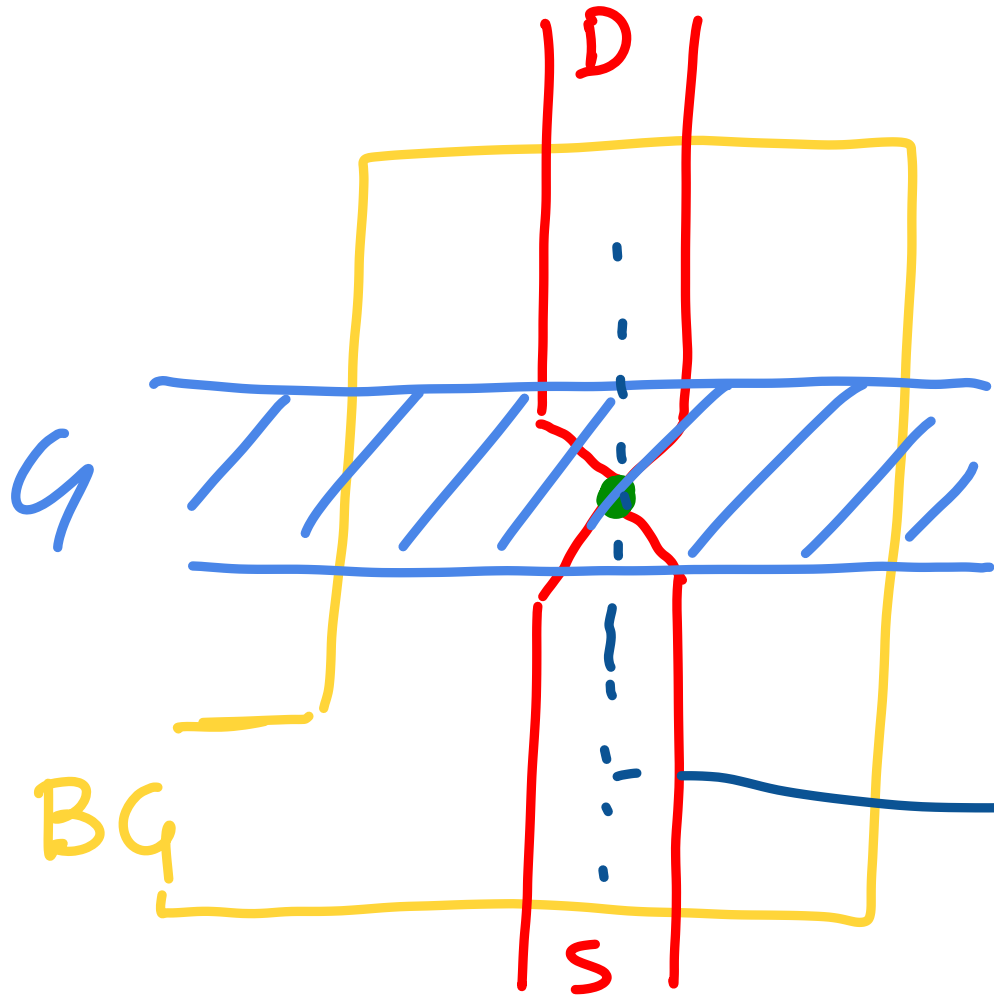
POWER SUPPLY

MT.
PRESENT
OR NOT

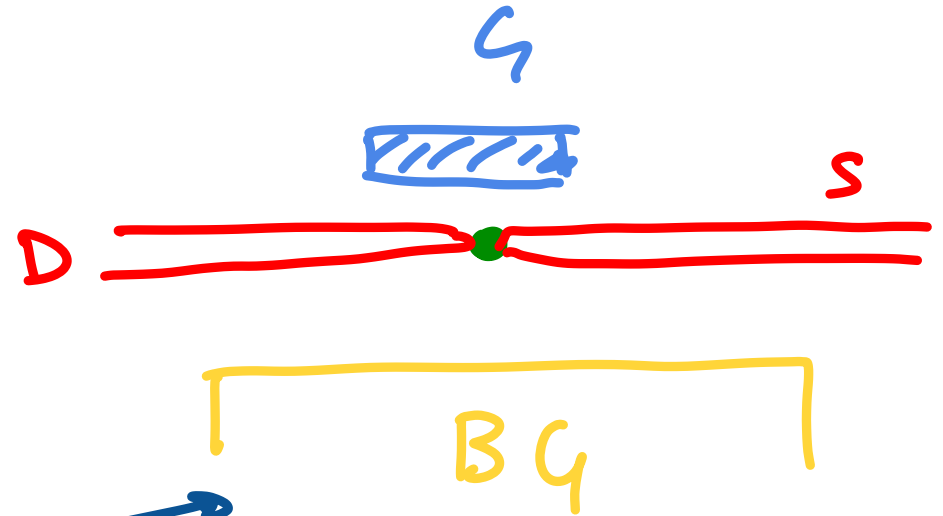


NOT IN
PARALLEL
OR
IN SERIES

1 SINGLE RT

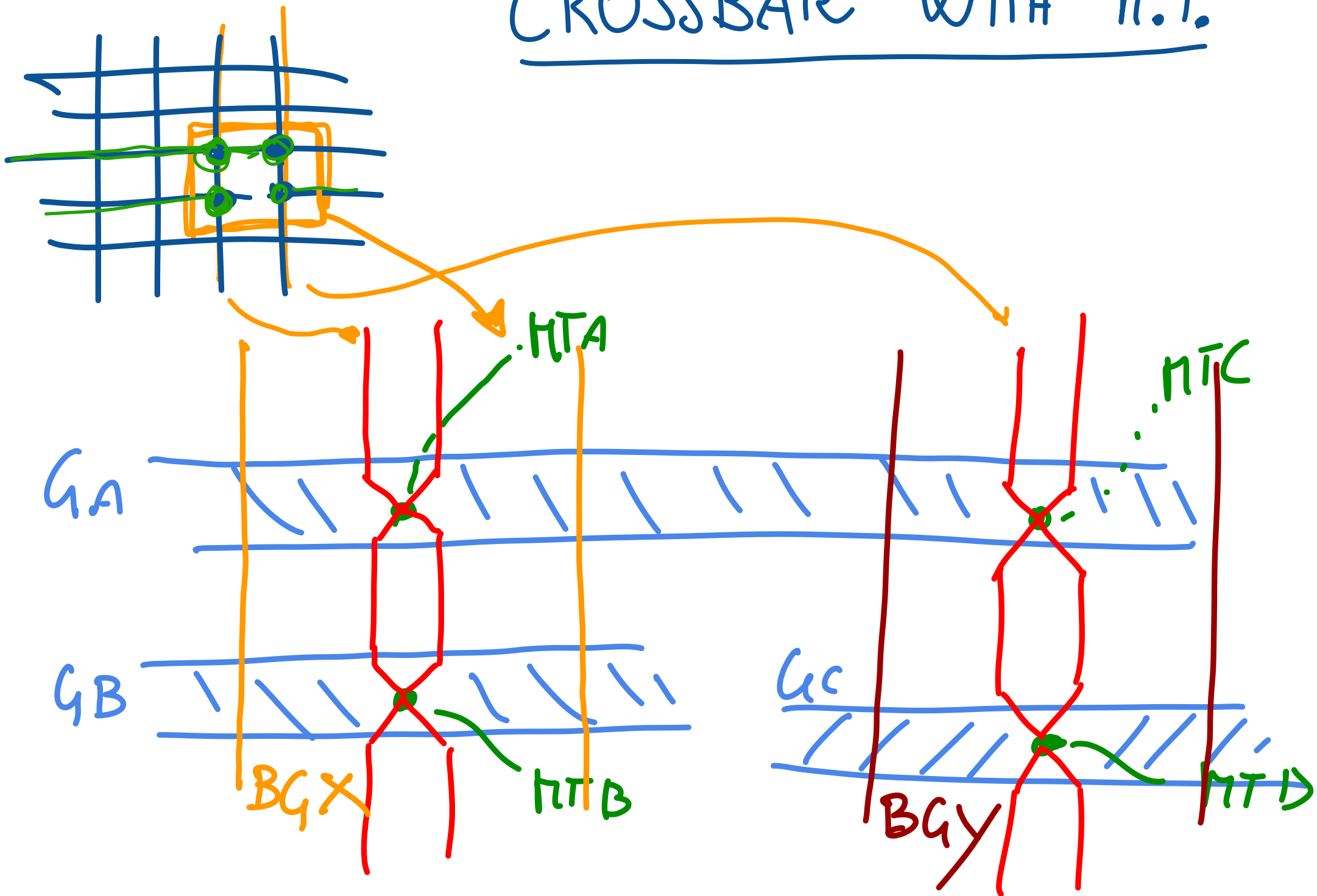


TOP VIEW



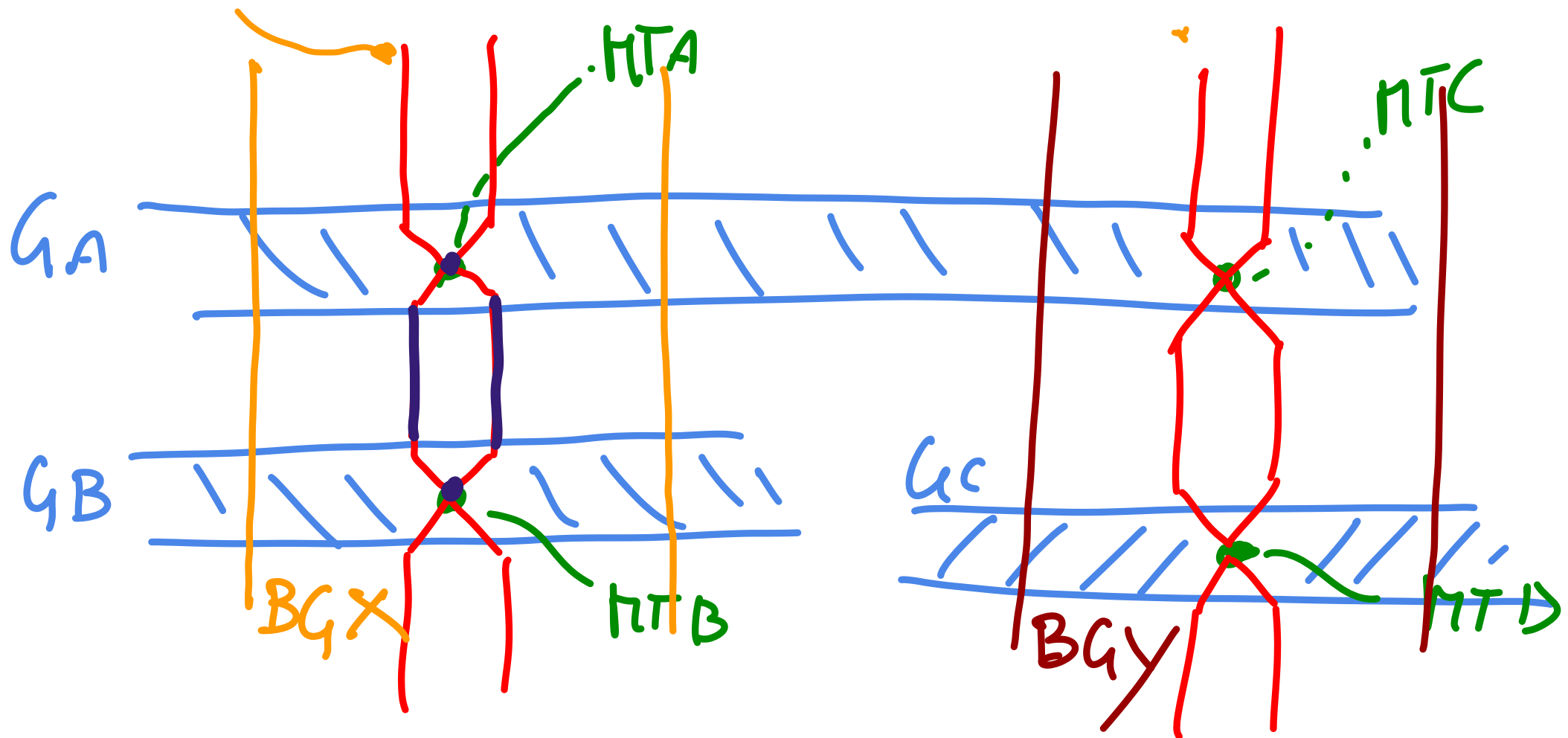
SECTION VIEW

CROSSBAR WITH M.T.

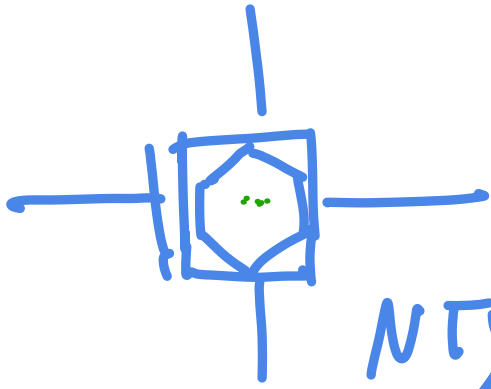


CONFIGURABLE BEHAVIOR

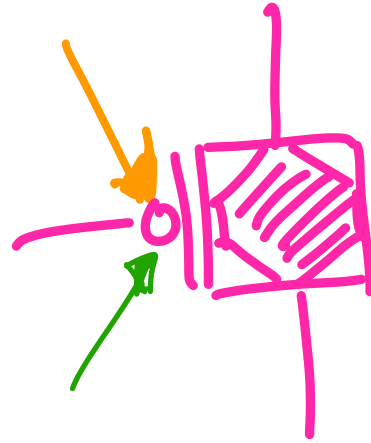
→ SAME MOLECULE IN THE WHOLE CIRCUIT
BUT DIFFERENT V_{BG} TO CHANGE THE
BEHAVIOR (PEAK INCLUDED IN BW)



SYMBOLS

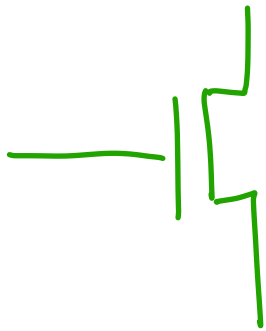


N TYPE
M.T

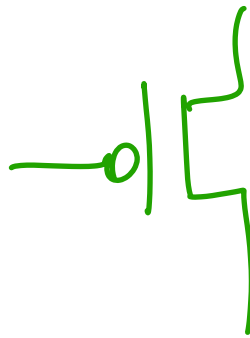


P TYPE
M.T

d

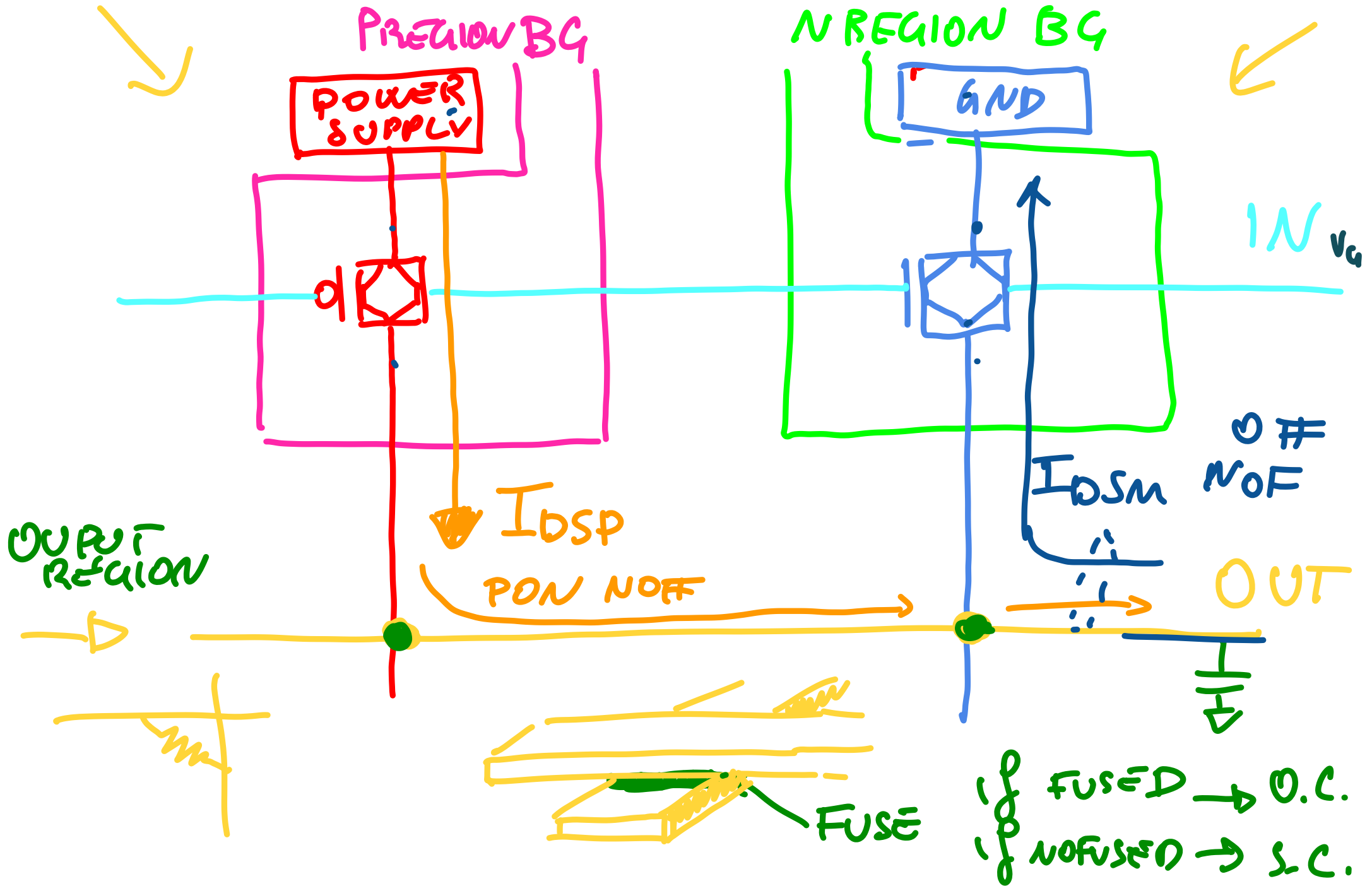


NMOS



PMOS

INVERTER BASED ON π .T.



NOTE: DIFFERENT ZONES FOR P&N
FACILITATE DIFFERENT V_{BQ} CONTROL
& DIFFERENT β COUPLING FACTORS

ex OPV7

$V_G = 0V$

N_{MT} OFF P_{MT} ON

V_{DS} ACTIVE

OUT $0 \rightarrow 1$

I_{Dsp} CHARGES
OUTPUT

\rightarrow V_{OUT} ?

VALUE
DEPENDS

CAP @ OUT, R_{PATH} !

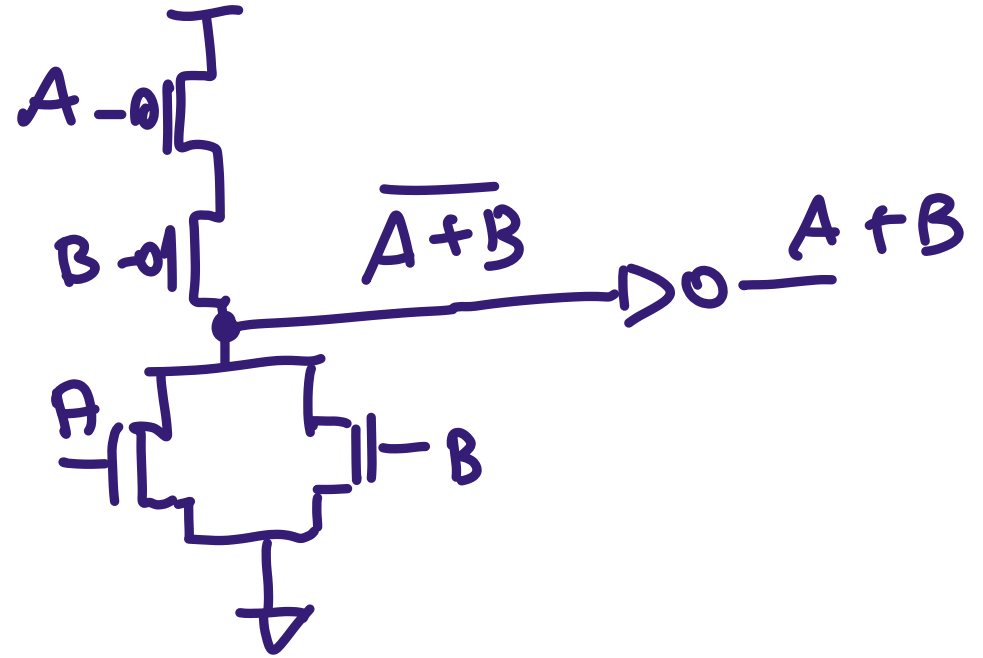
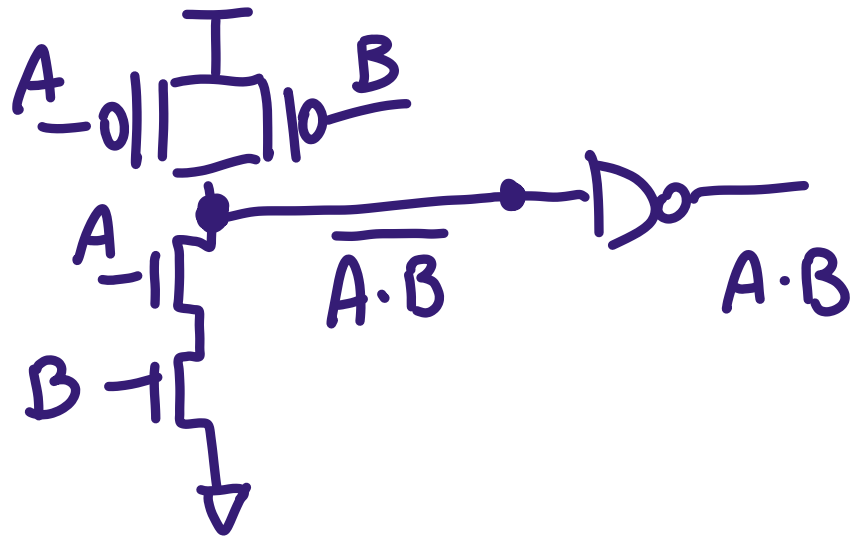
$V_G = 1V$

N_{MT} ON P_{MT} OFF

OUT $1 \rightarrow 0$

I_{Dsp} DISCHARGES
OUT

HOW TO FOR MORE COMPLEX LOGIC GATES?



$A \oplus B$

HALF-ADDER

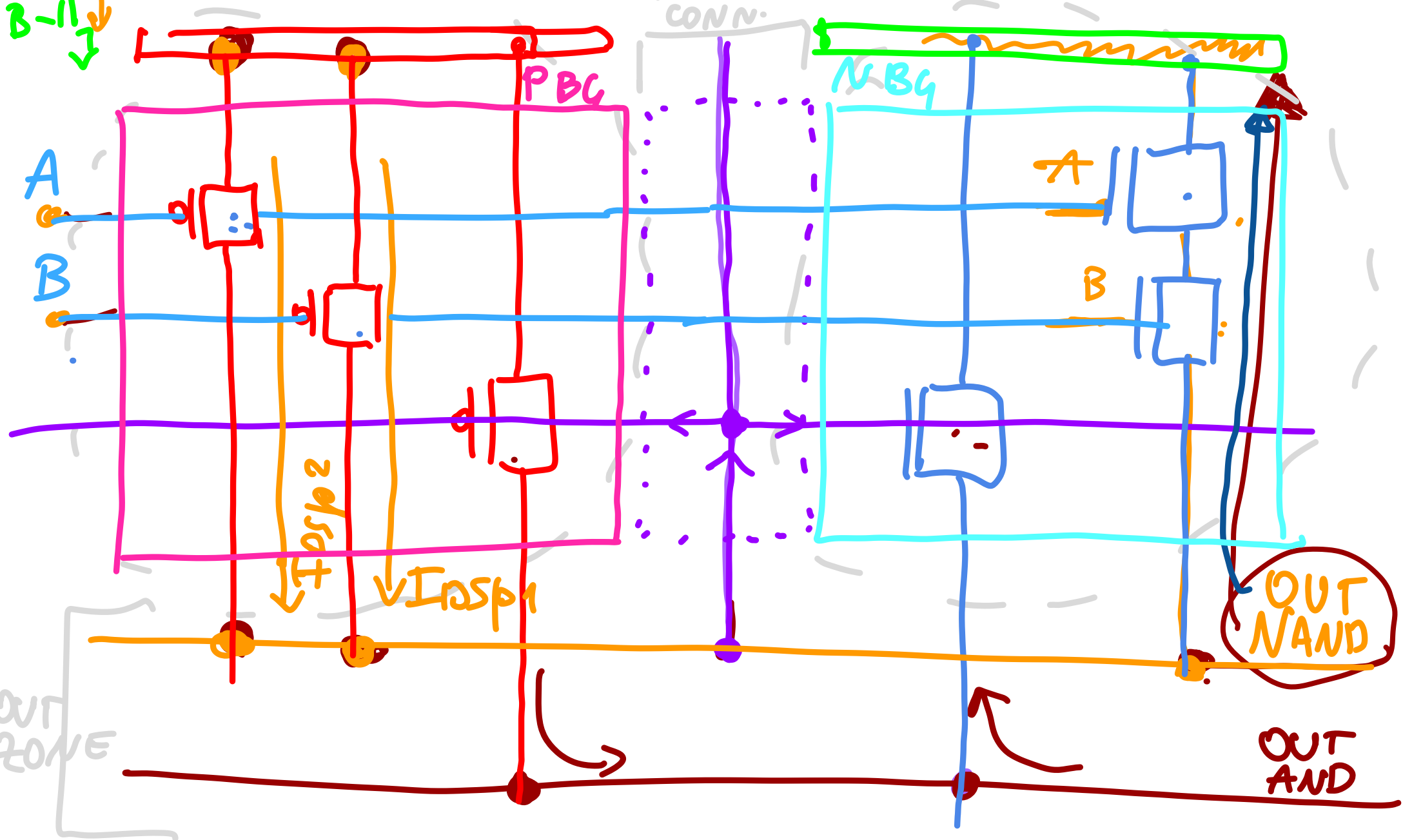
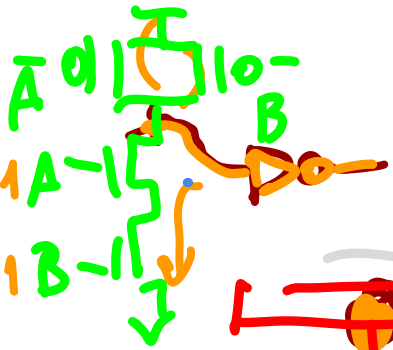
$A \oplus \overline{B}$

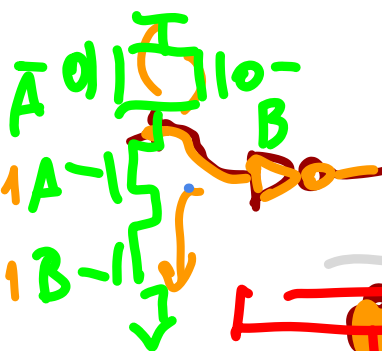
FULL ADDER

RIPPLE CARRY
ADDER

→ Work on them in the exercise section

NAND - AND GATES



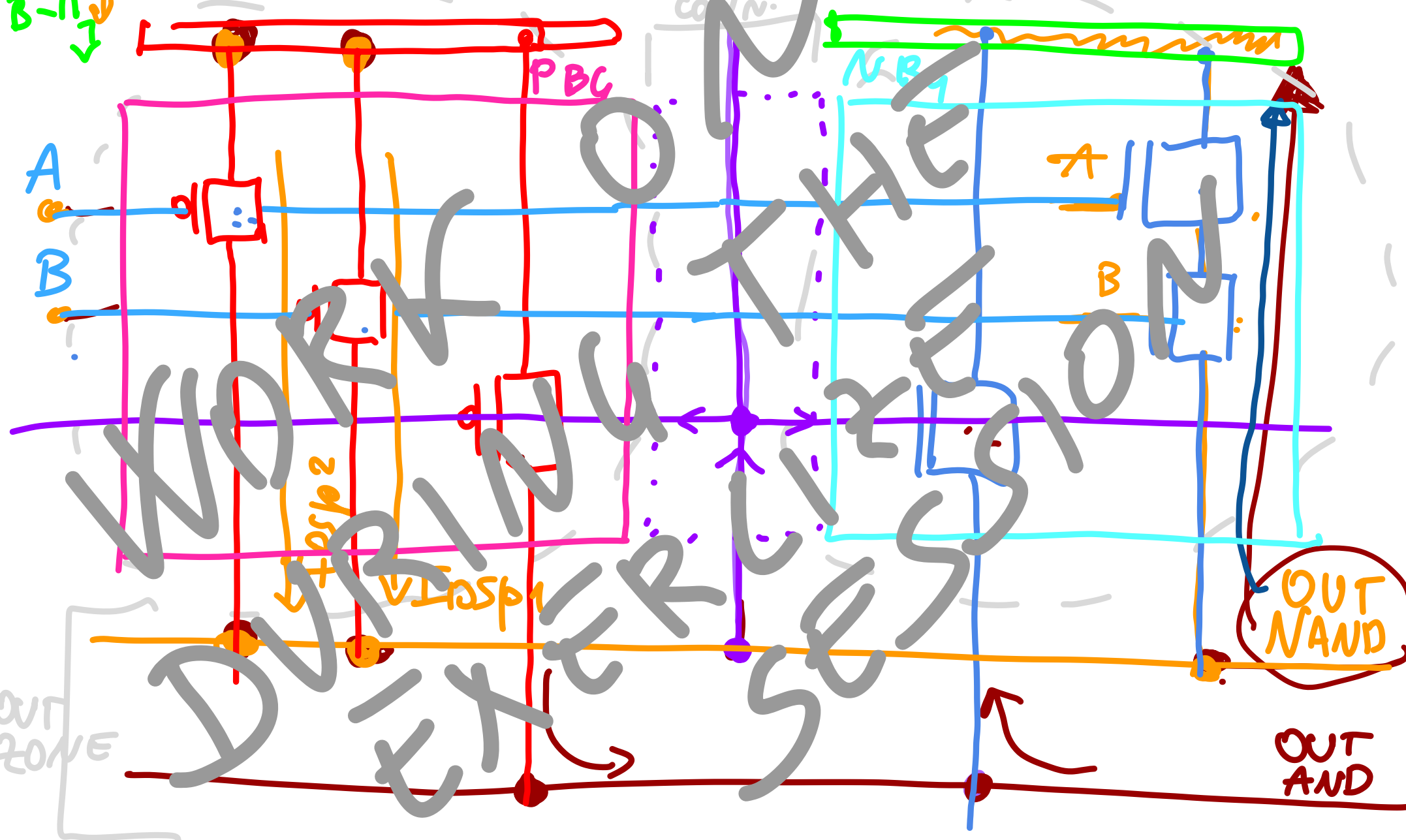


VTT, NAND

A AND

SAFE STAGE

INTERNAL CONN.



OUT ZONE

OUT AND

P TYPE NT ZONE

INTERNAL
INTERC. ZONE

N TYPE PT ZONE

HIGH VOLTAGE

LOW VOLTAGE



OUTPUT AND INTERMEDIATE FUNCTIONS ZONE

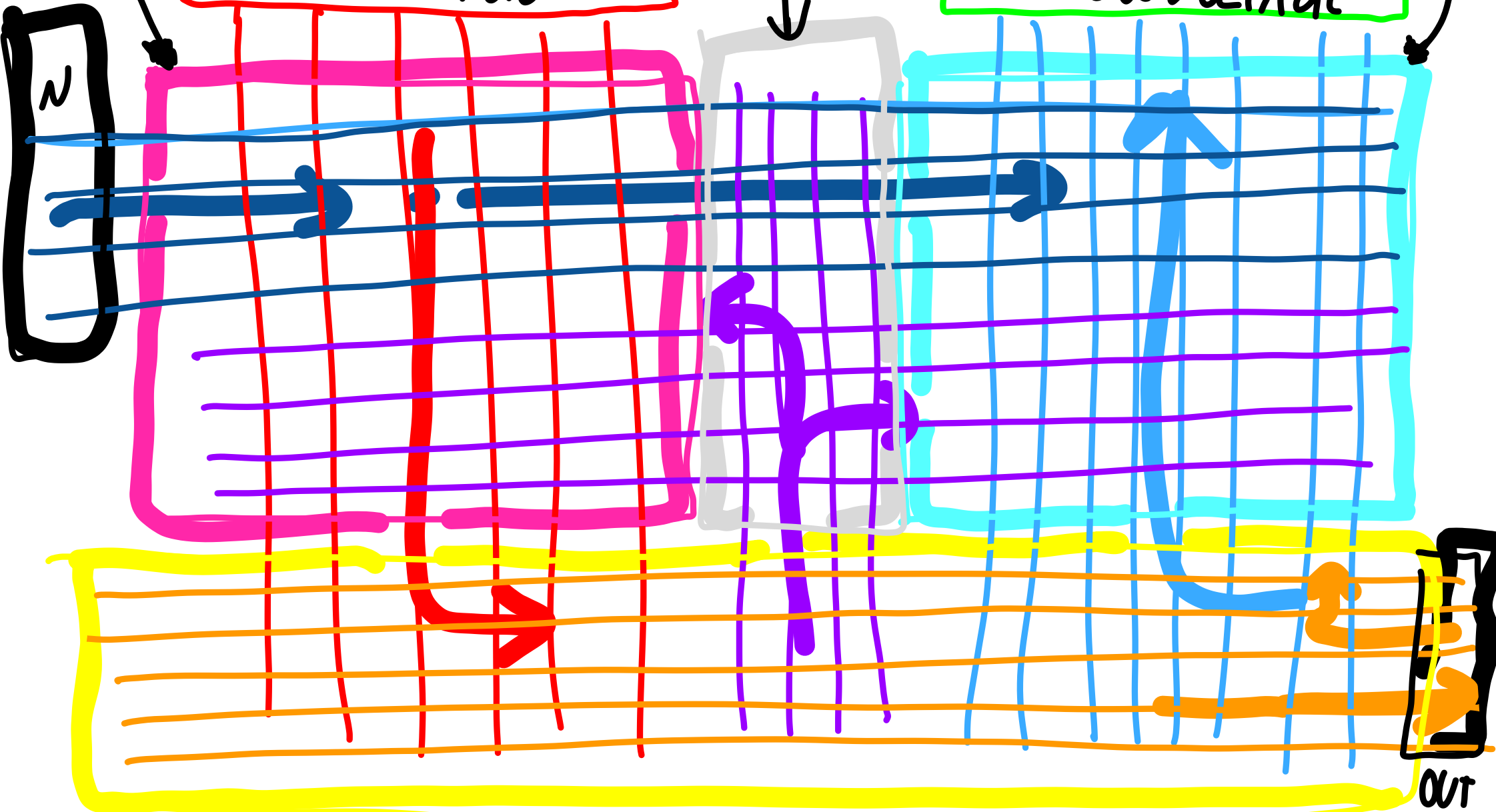
P-TYPE Π ΖΩΝΕ

INTERNAL
INTERC. ZONE

N-TYPE Π ΖΩΝΕ

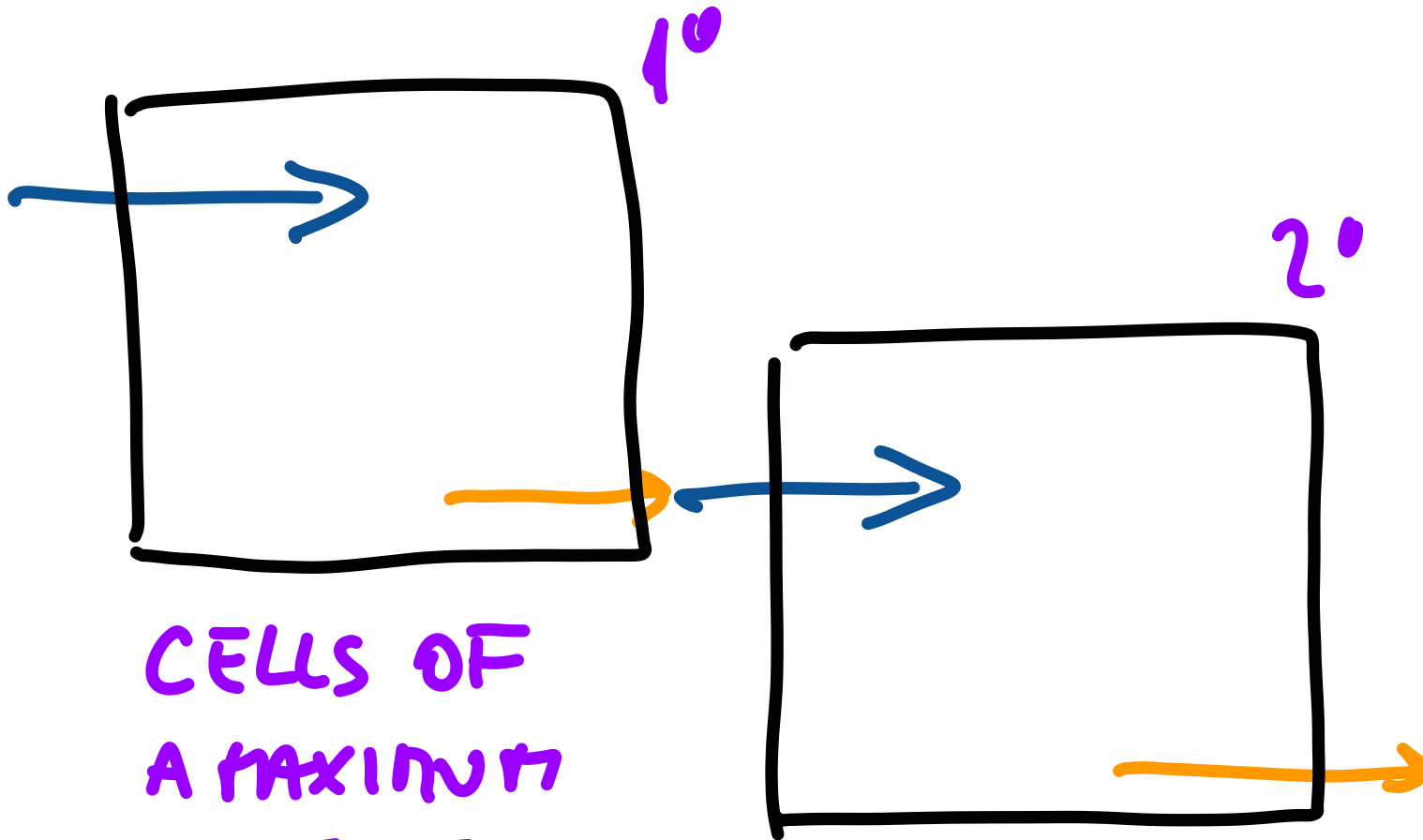
HIGH VOLTAGE

LOW VOLTAGE



OUTPUT AND INTERMEDIATE FUNCTIONS ZONE

CASCADING IS POSSIBLE



CELLS OF
A MAXIMUM
SIZE FOR
A CERTAIN NO^o
OF TR &
FUNCTIONS

WHAT ARE WE NEGLECTING?

→ INTERCONNECT PARASITICS

— RESISTANCES

— CAPACITANCES

→ DRIVING CAPABILITY OF
GATES/TRANSISTORS

→ NUMBER OF CASCADED
GATES

CRISTALLIZATION

2) SCF LOOP

3) SIMPLE
CIRCUITS BASED ON RT